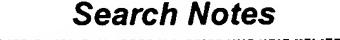


<b>Search Notes</b> 	<b>Application/Control No.</b> 10/730,322	<b>Applicant(s)/Patent under Reexamination</b> KATOH ET AL.
<b>Examiner</b> Shih-Chao Chen	<b>Art Unit</b> 2821	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
343	702	8/15/2005	CHEN
343	700MS	8/15/2005	CHEN